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10/587268**IAP11 Rec'd 07/27/2006**Sheet 1 of 4

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128865		APPLICATION NO. New U.S. National Phase of PCT/JP2005/001225	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Hiraki TAKAIWA et al.			
				FILING DATE July 26, 2006			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
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	2	2005/0024609 A1	02/03/2005	De Smit et al.			
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	20	W/O 2004/053858 A1	06/24/2004	WIPO	Y		
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Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER				DATE CONSIDERED			
/Michael Liu/				06/06/2008			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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